

Search Notes

Application/Control No.

10/622,029

Examiner

Quoc A. Tran

Applicant(s)/Patent under
Reexamination

TAKIZAWA ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	523	8/10/2005	
707	200	8/10/2005	
717	114	8/10/2005	
709	204	8/10/2005	
715	511	1/31/2006	
707	1	1/31/2006	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
INVENTORS SEARCH CHECK FOR DOUBLE PATENT	8/10/2005	
EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB See Search Histoty Printout	8/10/2005	
EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB See Search Histoty Printout	1/31/2006	
ACM DataBase See Search Histoty Printout	1/31/2006	